

Page i

RESISTORS, FIXED, SURFACE MOUNT, FILM, NON-HERMETICALLY SEALED, BASED ON TYPE SMC3

ESCC Detail Specification No. 4001/021

ISSUE 1 October 2002





ESCC Detail Specification

PAGE	ii
ISSUE	1

LEGAL DISCLAIMER AND COPYRIGHT

European Space Agency, Copyright © 2002. All rights reserved.

The European Space Agency disclaims any liability or responsibility, to any person or entity, with respect to any loss or damage caused, or allleged to be caused, directly or indirectly by the use and application of this ESCC publication.

This publication, without the prior permission of the European Space Ageny and provided that it is not used for a commercial purpose, may be:

- copied in whole in any medium without alteration or modification.
- copied in part, in any medium, provided that the ESCC document identification, comprising the ESCC symbol, document number and document issue, is removed.



european space agency agence spatiale européenne

Pages 1 to 17

RESISTORS, FIXED, SURFACE MOUNT, FILM, NON-HERMETICALLY SEALED, BASED ON TYPE SMC3

ESA/SCC Detail Specification No. 4001/021



space components coordination group

		Approved by		
Issue/Rev.	Date	SCCG Chairman	ESA Director General or his Deputy	
Issue 1	April 1996	Panonces	Houm	
Revision 'A'	November 1997	Sa milt	Com	



Rev. 'A'

PAGE 2

ISSUE 1

DOCUMENTATION CHANGE NOTICE

Rev. Letter	Rev. Date	Reference	CHANGE Item	Approved DCR No.
'A'	Nov. '97	P1. Cover page P2. DCN P4. T of C P6. Table 1(a) P10. Para. 4.5.2.3 P12. Table 3 P15. Table 6 P17.	: Page count increased by 1 : Appendix 'A' added : Item 04 minimum resistance amended : Items 07 to 09 added : Temperature Coefficient for ±15 added : Nos. 2 and 3, ±15 requirements added to Test Conditions and Limits : No. 4, Limits for ±15 added : Appendix 'A' added with new page	None None 221417 221411 221411 221411 221417



PAGE 3

ISSUE 1

TABLE OF CONTENTS

1.	GENERAL	<u>Page</u> 5
1.1 1.2 1.3	Scope Range of Components Maximum Ratings	5 5 5
1.4	Parameter Derating Information	5
1.5 1.6	Physical Dimensions	5 5
1.0	Functional Diagram	5
2.	APPLICABLE DOCUMENTS	5
3.	TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS	5
4.	REQUIREMENTS	8
4.1	General	8
4.2	Deviations from Generic Specification	8
4.2.1	Deviations from Special In-process Controls	8
4.2.2	Deviations from Final Production Tests	8
4.2.3	Deviations from Burn-in and Electrical Measurements	8
4.2.4	Deviations from Qualification Tests	8
4.2.5	Deviations from Lot Acceptance Tests	8
4.3	Mechanical Requirements	8
4.3.1	Dimension Check	8
4.3.2	Weight	8
4.3.3	Robustness of Terminations	9
4.4	Materials and Finishes	9
4.4.1	Case	9
4.4.2	Terminations	9
4.4.3	Films	9
4.5	Marking	9
4.5.1	General	9
4.5.2	Electrical Characteristics and Ratings	9
4.5.3	The SCC Component Number	10
4.5.4	Traceability Information	11
4.6	Electrical Measurements	11
4.6.1	Electrical Measurements at Room Temperature	11
4.6.2	Electrical Measurements at High and Low Temperatures	11
4.6.3	Circuits for Electrical Measurements	11
4.7	Burn-in Tests	11
4.7.1	Parameter Drift Values	11
4.7.2	Conditions for Burn-in	11
4.7.3	Electrical Circuit for Burn-in	11
4.8	Environmental and Endurance Tests	14
4.8.1	Measurements and Inspections on Completion of Environmental Tests	14
4.8.2	Measurements and Inspections at Intermediate Points during Endurance Tests	14
4.8.3	Measurements and Inspections on Completion of Endurance Tests	14
4.8.4	Conditions for Operating Life Tests	14
4.8.5	Electrical Circuit for Operating Life Tests	14
4.8.6	Conditions for High Temperature Storage Test	14



Rev. 'A'

PAGE 4 ISSUE 1

TABLES		<u>Page</u>
1(a)	Range of Components	6
1(b)	Maximum Ratings	6
2	Electrical Measurements at Room Temperature	12
3	Electrical Measurements at High and Low Temperatures	12
4	Parameter Drift Values	12
5	Conditions for Burn-in and Operating Life Tests	13
6	Measurements and Inspections on Completion of Environmental Tests and at Intermediate Points and on Completion of Endurance Testing	15
FIGURE	<u>s</u>	
1	Parameter Derating Information	7
2	Physical Dimensions	7
3	Functional Diagram	7
4	Circuits for Electrical Measurements	N/A
5	Electrical Circuit for Burn-in and Operating Life Tests	13
	DICES (Applicable to specific Manufacturers only)	
'A'	Agreed Deviations for Sfernice (F)	17



PAGE

ISSUE 1

5

1. GENERAL

1.1 SCOPE

This specification details the ratings, physical and electrical characteristics, test and inspection data for Resistors, Fixed, Surface Mount, Film, Non-hermetically Sealed, based on Type SMC3. It shall be read in conjunction with ESA/SCC Generic Specification No. 4001, the requirements of which are supplemented herein.

1.2 RANGE OF COMPONENTS

The range of resistors covered by this specification is given in Table 1(a).

1.3 MAXIMUM RATINGS

The maximum ratings, which shall not be exceeded at any time during use or storage, applicable to the resistors specified herein, are as scheduled in Table 1(b).

1.4 PARAMETER DERATING INFORMATION

The parameter derating information applicable to the resistors specified herein is given in Figure 1.

1.5 PHYSICAL DIMENSIONS

The physical dimensions of the resistors specified herein, are shown in Figure 2.

1.6 FUNCTIONAL DIAGRAM

The functional diagram for the resistors specified herein, is shown in Figure 3.

2. APPLICABLE DOCUMENTS

The following documents form part of this specification and shall be read in conjunction with it:-

(a) ESA/SCC Generic Specification No. 4001, Resistors, Fixed, Film.

3. TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS

For the purpose of this specification, the terms, definitions, abbreviations, symbols and units specified in ESA/SCC Basic Specification No. 21300 shall apply. In addition, the following symbols are used:-

 V_T = Test Voltage.

TC = Temperature Coefficient.



Rev. 'A'

PAGE 6 ISSUE 1

TABLE 1(a) - RANGE OF COMPONENTS

No.	Resistance Range (Note 1)		Tolerance (±%)	Value Series	Temperature Coefficient (±10 ⁻⁶ /°C)
	Min.	Max.	(± %)	Series	(±10 % C)
01	10Ω	1.0M Ω	0.1	E96	50
02	1.0Ω	1.0M Ω	0.5	E96	50
03	1.0Ω	1.0M Ω	1.0	E96	50
04	49.9 Ω	511k Ω	0.1	E96	25
05	49.9 Ω	511kΩ	0.5	E96	25
06	49.9 Ω	511kΩ	1.0	E96	25
07	49.9Ω	511kΩ	0.1	E96	15
08	49.9Ω	511kΩ	0.5	E96	15
09	49.9Ω	511kΩ	1.0	E96	15

NOTES

1. Critical resistance = 250 000 Ω .

TABLE 1(b) - MAXIMUM RATINGS

No.	Characteristics	Symbol	Limits	Unit	Remarks
1	Rated Dissipation	Pn	0.25	W	Note 1
2	Limiting Element Voltage	U_L	250	V	-
3	Rated Voltage	U _R	√ (0.25 R _n)	V	Note 2
4	Insulation Voltage	Ui	300	Vrms	-
5	Operating Temperature Range	T _{op}	−55 to +155	°C	T _{amb}
6	Storage Temperature Range	T _{stg}	−55 to +155	°C	-
7	Soldering Temperature	T _{sol}	+ 260	°C	Note 3

NOTES

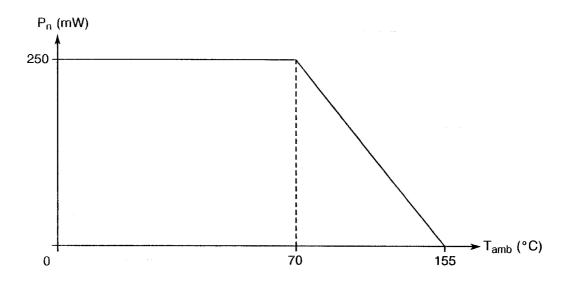
- 1. At $T_{amb} \le +70$ °C. For derating at $T_{amb} > +70$ °C, see Figure 1.
- 1. Shall never exceed Limiting Element Voltage.
- 2. Duration 10 seconds maximum.



PAGE 7

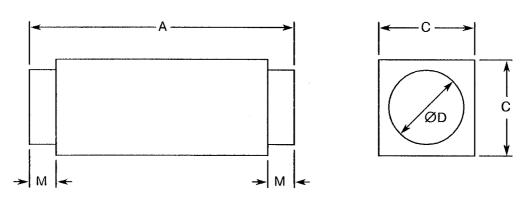
ISSUE 1

FIGURE 1 - PARAMETER DERATING INFORMATION



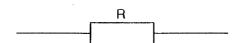
Rated Dissipation versus Temperature

FIGURE 2 - PHYSICAL DIMENSIONS



SYMBOL	MILLIMETRES		
STRIBUL	MIN.	MAX.	
Α	3.10	3.30	
С	1.50	1.70	
ØD	1.40	1.45	
M	0.45	0.65	

FIGURE 3 - FUNCTIONAL DIAGRAM





PAGE 8

ISSUE 1

4. REQUIREMENTS

4.1 GENERAL

The complete requirements for procurement of the resistors specified herein shall be as stated in this specification and ESA/SCC Generic Specification No. 4001. Deviations from the Generic Specification, applicable to this specification only, are listed in Para. 4.2.

Deviations from the applicable Generic Specification and this Detail Specification, formally agreed with specific Manufacturers on the basis that the alternative requirements are equivalent to the ESA/SCC requirements and do not affect the components' reliability, are listed in the appendices attached to this specification.

4.2 DEVIATIONS FROM GENERIC SPECIFICATION

4.2.1 Deviations from Special In-process Controls

None.

4.2.2 Deviations from Final Production Tests (Chart II)

(a) Para. 9.1, Overload: The test conditions shall be:-

Voltage: $\sqrt{0.375 R_n}$ or 250V, whichever is less.

Duration: 24 ± 2.0 hours.

4.2.3 Deviations from Burn-in and Electrical Measurements (Chart III)

None.

4.2.4 Deviations from Qualification Tests (Chart IV)

- (a) Para. 9.1, Overload: Test conditions as Para. 4.2.2(a) and in addition Resistance Change measurements shall be performed as given in Table 6 of this specification.
- (b) Para. 9.10.2.3, Bend Strength of the End Face Plating: Not applicable.
- (c) Para. 9.12, Rapid Change of Temperature: Not applicable.
- (d) Para. 9.13, Vibration: Not applicable.
- (e) Para. 9.19, Permanence of Marking: Not applicable.

4.2.5 Deviations from Lot Acceptance Tests (Chart V)

- (a) Para. 9.10.2.3, Bend Strength of the End Face Plating: Not applicable.
- (b) Para. 9.13, Vibration: Not applicable.
- (c) Para. 9.19, Permanence of Marking: Not applicable.

4.3 MECHANICAL REQUIREMENTS

4.3.1 Dimension Check

The dimensions of the resistors specified herein shall be verified in accordance with the requirements set out in Para. 9.4 of ESA/SCC Generic Specification No. 4001 and shall conform to those shown in Figure 2 of this specification.

4.3.2 Weight

The maximum weight of the resistors specified herein shall be 0.03 grammes.



PAGE

ISSUE 1

9

4.3.3 Robustness of Terminations

The requirements and test conditions for robustness of terminations are specified in Para. 9.10.2 of ESA/SCC Generic Specification No. 4001.

4.4 MATERIALS AND FINISHES

The materials and finishes shall be as specified herein. Where a definite material is not specified, a material which will enable the components specified herein to meet the performance requirements of this specification shall be used. Acceptance or approval of any constituent material does not guarantee acceptance of the finished product.

4.4.1 <u>Case</u>

As a minimum, the resistance element shall be protected by a suitable inorganic coating.

4.4.2 <u>Terminations</u>

The end-cap material shall be nickel/copper/zinc alloy, nickel plated with tin-lead plated finish (minimum 10% lead).

4.4.3 Films

Films shall be uniformly deposited. They shall be free from blisters, thin spots, areas inadequately bonded to the core, discoloured spots or other blemishes likely to cause flaking or non-uniform ribbons when spiralled (helixed). When used, spiralling shall occupy at least 70% of the active length of the resistance element.

4.5 MARKING

4.5.1 General

The marking of all components delivered to this specification shall be in accordance with the requirements of ESA/SCC Basic Specification No. 21700 and the following paragraphs. When the component is too small to accommodate all of the marking specified, as much as space permits shall be marked and the marking information, in full, shall accompany each component in its primary package.

The information to be marked and the order of precedence, shall be as follows:-

- (a) Electrical Characteristics and Ratings.
- (b) The SCC Component Number.
- (c) Traceability Information.

4.5.2 Electrical Characteristics and Ratings

The electrical characteristics and ratings to be marked in the following order of precedence are:-

- (a) Resistance Value.
- (b) Tolerance.
- (c) Temperature Coefficient.

The information shall be constituted and marked as follows:

	2490F3
Value (249 Ohms)	
Tolerance (±1.0%)	
Temperature Coefficient (±50	0 10 ⁻⁶ /°C)



Rev. 'A'

PAGE 10 ISSUE 1

4.5.2.1 Resistance Values

Resistance values shall be expressed by means of the following codes. The unit quantity for marking shall be Ohms (Ω) .

Resistance Value	Code
XX.X	XXRX
XXX	XXX0
XXX10 ¹	XXX1
XXX10 ²	XXX2
XXX10 ³	XXX3
XXX10 ⁴	XXX4

For values of 100Ω and above, the first 3 digits (X) represent significant figures and the last digit specifies the number of zeros to follow.

When values of less than 100Ω are required, the letter 'R' is used to indicate the decimal point. When the letter is used, all successive digits represent significant figures.

4.5.2.2 Tolerance

The tolerance on resistance values shall be indicated by the code letters specified hereafter.

Tolerance (±%)	Code Letter
0.1	В
0.5	D
1.0	F

4.5.2.3 Temperature Coefficient

The temperature Coefficient shall be indicated by the numerical codes specified hereafter.

Digit	Temperature Coefficient (±10-6/°C)
1	15
2	25
3	50

4.5.3 The SCC Component Number

Each component shall bear the SCC Component Number which shall be constituted and marked as follows:

	<u>400102101</u> E	4
Detail Specification Number ———		
Type Variant (see Note)	The second secon	
Testing Level (B or C, as applicable)		

N.B

Marking of the Type Variant Number is mandatory. No further reference to type variants is made in this specification.



PAGE 11

ISSUE 1

4.5.4 Traceability Information

Each component shall be marked in respect of traceability information in accordance with the requirements of ESA/SCC Basic Specification No. 21700.

4.6 ELECTRICAL MEASUREMENTS

4.6.1 Electrical Measurements at Room Temperature

The parameters to be measured at room temperature are scheduled in Table 2. Unless otherwise specified, the measurements shall be performed at $T_{amb} = +22 \pm 3$ °C.

4.6.2 <u>Electrical Measurements at High and Low Temperatures</u>

The parameters to be measured on a sample basis at high and low temperatures are scheduled in Table 3.

The distribution of the sample shall be as follows:

- 1/3 with the lowest resistance value,
- 1/3 with the highest resistance value,
- 1/3 with the median resistance value or the critical resistance value if procured,

of the procured range.

4.6.3 <u>Circuits for Electrical Measurements (Figure 4)</u>

Not applicable.

4.7 BURN-IN TESTS

4.7.1 Parameter Drift Values

The parameter drift values applicable to burn-in are specified in Table 4 of this specification. Unless otherwise stated, measurements shall be performed at T_{amb} = +22 ± 3 °C. The parameter drift values (Δ) applicable to the parameters scheduled, shall not be exceeded. In addition to these drift value requirements, the appropriate limit value specified in Table 2 for a given parameter shall not be exceeded.

4.7.2 Conditions for Burn-in

The requirements for burn-in are specified in Section 7 of ESA/SCC Generic Specification No. 4001. The conditions for burn-in shall be as specified in Table 5 of this specification.

After 168(+24-0) hours, the resistors shall be removed from the chamber and allowed to cool under normal atmospheric conditions for a minimum of 4 hours. They shall then be visually examined. There shall be no evidence of damage and the marking shall still be legible.

4.7.3 Electrical Circuit for Burn-in

The circuit for use in performing the burn-in test is shown in Figure 5 of this specification.



Rev. 'A'

PAGE 12 ISSUE 1

TABLE 2 - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE

No.	Characteristics	Symbol	ESA/SCC 4001 Test		Test Tolerance		nits	Unit
INO.	Orlaracteristics	Symbol	Test Method	Conditions	(±%)	Min.	Max.	Othic
1	Resistance	R_A	Para. 9.5.1	Para. 9.5.1	0.1	0.999 R _n	1.001 R _n	Ω
					0.5	0.995 R _n	1.005 R _n	·
					1.0	0.990 R _n	1.010 R _n	

TABLE 3 - ELECTRICAL MEASUREMENTS AT HIGH AND LOW TEMPERATURES

No	Characteristics	Symbol	ESA/SCC 4001	Test Conditions	Lin	Unit	
INO.	No. Characteristics Sym		Symbol Test Method		Min.	Max.	Offic
2	Resistance Change between -55(+3-0) °C and +22±3 °C	<u>ΔR</u> R	Para. 9.5.1	Para. 9.5.1 ± 15 10 - 6/° C ± 25 10 - 6/° C ± 50 10 - 6/° C	- 0.12 - 0.20 - 0.40	+ 0.12 + 0.20 + 0.40	%
3	Resistance Change between +155(+0-3) °C and +22±3 °C	<u>ΔR</u> R	Para. 9.5.1	Para. 9.5.1 ±15 10-6/°C ±25 10-6/°C ±50 10-6/°C	- 0.20 - 0.35 - 0.70	+0.20 +0.35 +0.70	%

NOTES

FIGURE 4 - CIRCUITS FOR ELECTRICAL MEASUREMENTS

Not applicable.

TABLE 4 - PARAMETER DRIFT VALUES

No.	Characteristics	Symbol	Spec. and/or Test Method	Test Conditions	Change Limits (Δ)	Unit
1	Resistance Change	<u>ΔR</u> _A R _A	As per Table 2	As per Table 2	± 0.25 or (1) ± 0.05	% Ω

NOTES

1. Whichever is greater.

^{1.} The measurements shall be performed on a sample basis in accordance with General Inspection Level II, Table IIA, AQL = 0.65% of IEC Publication No. 410 on the total production lot. In addition, see Para. 4.6.2 for distribution of the sample.



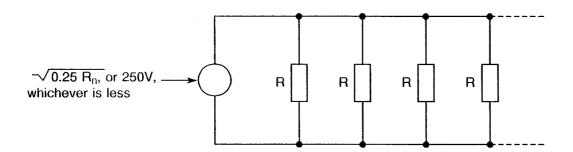
PAGE 13

ISSUE 1

TABLE 5 - CONDITIONS FOR BURN-IN AND OPERATING LIFE TESTS

No.	Characteristics	Symbol	Condition	Unit
1	Ambient Temperature	T _{amb}	+70±3	°C
2	Test Voltage	V _T	√ 0.25 R _n , or 250V, whichever is less	V

FIGURE 5 - ELECTRICAL CIRCUIT FOR BURN-IN AND OPERATING LIFE TESTS





PAGE 14

ISSUE

4.8 ENVIRONMENTAL AND ENDURANCE TESTS (CHARTS IV AND V OF ESA/SCC GENERIC SPECIFICATION No. 4001)

The resistors shall be mounted as prescribed in ESA/SCC Generic Specification No. 4001, Para. 9.20. The substrate material shall be epoxy glass laminated pointing board.

4.8.1 Measurements and Inspections on Completion of Environmental Tests

The parameters to be measured and inspections to be performed on completion of environmental tests are scheduled in Table 6. Unless otherwise stated, the measurements shall be performed at T_{amb} = +22 ±3 °C.

4.8.2 Measurements and Inspections at Intermediate Points during Endurance Tests

The parameters to be measured and inspections to be performed at intermediate points during endurance tests are as scheduled in Table 6 of this specification. Unless otherwise stated, the measurements shall be performed at $T_{amb} = +22 \pm 3$ °C.

4.8.3 Measurements and Inspections on Completion of Endurance Tests

The parameters to be measured and inspections to be performed on completion of endurance testing are as scheduled in Table 6 of this specification. Unless otherwise stated, the measurements shall be performed at $T_{amb} = +22 \pm 3$ °C.

4.8.4 Conditions for Operating Life Tests (Part of Endurance Testing)

The requirements for operating life testing are specified in Section 9 of ESA/SCC Generic Specification No. 4001. The conditions for operating life testing shall be as specified in Table 5 of this specification.

4.8.5 Electrical Circuits for Operating Life Tests

Circuits for use in performing the operating life tests are shown in Figure 5 of this specification.

4.8.6 Conditions for High Temperature Storage Test (Part of Endurance Testing)

The requirements for the high temperature storage test are specified in ESA/SCC Generic Specification No. 4001. The conditions for high temperature storage shall be $T_{amb} = +155(+0-5)$ °C.



Rev. 'A'

PAGE 15

ISSUE 1

TABLE 6 - MEASUREMENTS AND INSPECTIONS ON COMPLETION OF ENVIRONMENTAL TESTS AND AT INTERMEDIATE POINTS AND ON COMPLETION OF ENDURANCE TESTING

	ESA/SCC GENERIC S	SPEC. NO. 4001	MEASUREMENTS AN	ND INSPECTIONS		LIM	ITS	
NO.	ENVIRONMENTAL AND ENDURANCE TESTS (1)	TEST METHOD AND CONDITIONS	IDENTIFICATION	CONDITIONS	SYMBOL	MIN.	MAX.	UNIT
01	Overload	Para. 9.1 and Paras. 4.2.2 and 4.2.4 of this spec.	Initial Measurements Chart IV Resistance Final Measurements Visual Examination Chart II Resistance Chart IV	Table 2 Item 1 After a recovery period of 1-2 hrs No evidence of damage and marking legible Table 2 Item 1	R _A	Record - Table 2	-	-
			Resistance Change	Table 2 Item 1	ΔR _A /R _A	± (0.25 + <u>0.</u>	<u>05Ω×100</u>) Rn	%
02	Seal Test (Hermetically Sealed only)	Para. 9.3	Not applicable					
03	Insulation Resistance (Insulated only)	Para. 9.6	Final Measurements Insulation Resistance	Para. 9.6.2 of ESA/SCC 4001 (2)	Ri	1000	-	МΩ
04	Temperature Coefficient	Para. 9.7 Procedure I	Temperature Coefficient	Para. 9.5.1 of ESA/SCC 4001	TC	- 15 - 25 - 50	+ 15 + 25 + 50	10 ⁻⁶ / °C
05	Voltage Proof	Para. 9.8	During Test Visual Examination	1.4×U _i (3) for 60±5 sec No breakdown or flashover	-	-	-	- -
06	Solderability	Para. 9.9 Procedure I	Initial Measurements Resistance Final Measurements	After Drying Table 2 Item 1 24 ±4 hrs after soldering	R _A	Record	Values	
			Resistance Change	Table 2 Item 1	ΔR _A /R _A	<u>±</u> (0.15 + <u>0</u>	. <u>05Ω×100</u>) Rn	%
07	Robustness of Terminations	Para. 9.10.2 Adhesion	Initial Measurements Resistance Final Measurements Resistance Change Visual Examination	After Mounting Table 2 Item 1 Table 2 Item 1 No damage, lifting,	- R _A ΔR _A /R _A -		- Values [.05Ω×100) Rn -	- % -
		Paras 4.2.4 and 4.2.5 of this spec. Bend Strength of End Plate Facing	Not applicable	cracking or dry joints				
08	Resistance to Soldering Heat	Para. 9.11 Procedure I	Initial Measurements Resistance Final Measurements Visual Examination Resistance Change	After Drying Table 2 Item 1 No evidence of damage and marking legible After 24 ± 4 hours Table 2 Item 1	R _A - ΔR _A /R _A	-	Values05Ω×100) Rn	- %
09	Rapid Change of Temperature	Para. 9.12 and Para. 4.2:4 of this spec.	Not applicable					
10	Vibration	Para. 9.13 and Paras 4.2.4 and 4.2.5 of this spec.	Not applicable					

NOTES

- 1. The tests in this Table refer to either Chart ${\rm IV}$ or ${\rm V}$ and shall be used as applicable.
- 2. Test Voltage: $V_T = 100V$.
- 3. For value of U_i, see Table 1(b) Item 4.



PAGE 16

ISSUE 1

TABLE 6 - MEASUREMENTS AND INSPECTIONS ON COMPLETION OF ENVIRONMENTAL TESTS AND AT INTERMEDIATE POINTS AND ON COMPLETION OF ENDURANCE TESTING (CONT'D)

	ESA/SCC GENERIC S	SPEC. NO. 4001	MEASUREMENTS A	ND INSPECTIONS		LIM	ITS	
NO.	ENVIRONMENTAL AND ENDURANCE TESTS (1)	TEST METHOD AND CONDITIONS	IDENTIFICATION	CONDITIONS	SYMBOL	MIN.	MAX.	UNIT
11	Climatic Sequence	Para. 9.14 Procedure I	Initial Measurements Resistance Final Measurements	After Drying Table 2 Item 1 Following completion of D.C. load test and	R _A	Record	Values	
			Visual Examination	after a recovery period of 1-2 hrs No evidence of damage and marking legible	-	-	-	
			Insulation Resistance Resistance Change	Para. 9.6 of ESA/SCC 4001 (2) Table 2 Item 1	Ri ΔR _A /R _A	1000 + (0.5 + 0.0	- 05Ω×100)	MΩ %
			g		A	_ (= = = = = = = = = = = = = = = = = = =	Rn	, ,
12	Operating Life	Para. 9.15 Chart IV	Initial Measurements Resistance Intermediate Measurements (1000 hrs)	Table 2 Item 1 After a recovery period of 1-2 hrs	R_A	Record	Values	
			Visual Exámination Resistance Change	No evidence of damage Table 2 Item 1	- ΔR _A /R _A	- ± (0.35 + <u>0.</u>	- 05Ω×100)	- %
			Final Measurements (2000 hrs) Visual Examination	After a recovery period of 1-2 hrs No evidence of	-	-	Rn -	-
			Resistance Change	damage Table 2 Item 1	$\Delta R_A/R_A$	± (0.5 + <u>0.0</u>		%
			Insulation Resistance	Para. 9.6 of ESA/SCC 4001 (2)	Ri	1000	Rn -	МΩ
		Para. 9.15 Chart V	Initial Measurements Resistance Final Measurements (1000 hrs) Visual Examination	Table 2 Item 1 After a recovery period of 1-2 hrs No evidence of	R_{A}	Record	Values	
			Resistance Change	damage Table 2 Item 1	$\Delta R_A/R_A$. (0.25.10	05Ω×100)	- %
				Para. 9.6 of	Δη _Α /η _Α Ri		Rn	/° ΜΩ
			Insulation Resistance	ESA/SCC 4001 (2)	NI NI	1000	-	10152
13	High Temperature Storage	Para. 9.16	Initial Measurements Resistance Intermediate Measurements	Table 2 Item 1 After a recovery period of 1-2 hrs	R _A	Record	Values -	
			(1000 hrs) Visual Examination	No evidence of	-			-
			Resistance Change	damage Table 2 Item 1	$\Delta R_A/R_A$	± (0.35 + <u>0.</u>	05Ω×100) Rn	%
			Final Measurements (2000 hrs) Visual Examination	After a recovery period of 1-2 hrs No evidence of damage	-	-	-	-
			Resistance Change	Table 2 Item 1	$\Delta R_A/R_A$	± (0.5 + <u>0.0</u>	05Ω×100) Rn	%
			Insulation Resistance	Para. 9.6 of ESA/SCC 4001 (2)	Ri	1000		МΩ
14	Permanence of Marking	Para. 9.19 and Para. 4.2.4 of this spec.	Not applicable					

NOTES: See Page 15.



Rev. 'A'

PAGE 17

ISSUE 1

APPENDIX 'A'

Page 1 of 1

AGREED DEVIATIONS FOR SFERNICE (F)

ITEMS AFFECTED	DESCRIPTION OF DEVIATIONS
Para. 4.2.2	Para. 4.4, Marking: The Type Variant defined in Para. 4.5.3 of this specification need not be marked on the component.